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INTERNATIONAL STANDARD

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Metallic communication cable test methods – Part 4-10: Electromagnetic compatibility (EMC) – Transfer impedance and screening attenuation of feed-throughs and electromagnetic gaskets – Double coaxial test method

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CONTENTS

FOREWORD 4
1 Scope 6
2 Normative references 6
3 Terms and definitions 6
4 Principle of the test method 9
5 Procedure 12
5.1 Equipment 12
5.2 Dynamic range 12
5.3 Verification of the test set-up 12
5.4 Sample preparation 12
6 Measurement 12
6.1 General 12
6.2 Screening attenuation 12
6.3 Transfer impedance 12
7 Expression of results 13
7.1 Transfer impedance 13
7.2 Screening attenuation 13
7.3 Requirements 13
Annex A (informative) Background for the measurement of the shielding effectiveness of feed-throughs and electromagnetic gaskets 14
A.1 General 14
A.2 Theoretical model of the test procedure 15
A.3 Performing measurements 16
A.3.1 Characteristic impedance uniformity of the test fixture 16
A.3.2 Measuring EMI-gaskets by using a NWA 16
A.3.3 Pictures and measurement results 17
Annex B (informative) Reference device for verification measurement 23
B.1 General 23
B.2 Design of the reference device 23
B.3 Verification measurement result 24
Annex C (informative) Impact of ground loops on low frequency measurements 25
C.1 General 25
C.2 Analysis of the test set-up 25
Bibliography 28

Figure 1 – A two-port 7
Figure 2 – Equivalent circuit of the test set-up and definition of Z_T 7
Figure 3 – Cross-section of a typical feed-through configuration 10
Figure 4 – Cross-section of the test fixture with a connector 10
Figure 5 – Cross-section of the test fixture with an electromagnetic gasket 11
Figure A.1 – Cross-section of a typical feed-through configuration 14
Figure A.2 – Cross-section of the test fixture with a connector 15
Figure A.3 – Equivalent circuit of the test setup with the shunt admittance *y* of the feed-through 15

Figure A.4 – TDR step response at input-port of test fixture 16
Figure A.5 – View of the test fixture connected to a network analyzer 18
Figure A.6 – Top view of the test fixture 18
Figure A.7 – Detailed view of the contact area 18
Figure A.8 – Detailed view of the captivation for the conductive O-ring test 19
Figure A.9 – Isolation of the network analyzer 20
Figure A.10 – Isolation of the test fixture when characterizing an ideal short (metal plate) 20
Figure A.11 – Measured operational screening transmission when characterizing a typical conductive O-ring 21
Figure A.12 – Transfer impedance Z_T of a typical conductive O-ring 21
Figure A.13 – Screening attenuation a_S of a typical conductive O-ring 22
Figure B.1 – Reference device, e.g. resistors soldered onto a PCB 23
Figure B.2 – Typical verification measurement result 24
Figure C.1 – Double coaxial test set-up 25
Figure C.2 – Equivalent circuits of the double coaxial test set-up 26
Figure C.3 – Results obtained with (green) and without ferrites on the test leads (blue) 27

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METALLIC COMMUNICATION CABLE TEST METHODS –

Part 4-10: Electromagnetic compatibility (EMC) – Transfer impedance and screening attenuation of feed-throughs and electromagnetic gaskets – Double coaxial test method

FOREWORD

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International Standard IEC 62153-4-10 has been prepared by IEC technical committee 46: Cables, wires, waveguides, R.F. connectors, R.F. and microwave passive components and accessories.

This second edition cancels and replaces the first edition published in 2009. It constitutes a technical revision.

The main technical changes with regard to the previous edition are as follows:

– addition of a new clause that describes a procedure for verification of the measurement set-up and further information regarding sample preparation;

– addition of a new Annex that describes how to improve measurement certainty in the very low frequency area.

The text of this standard is based on the following documents:

FDIS	Report on voting
46/563/FDIS	46/580/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of the IEC 62153 series, under the general title: *Metallic communication cable test methods*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC website under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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METALLIC COMMUNICATION CABLE TEST METHODS –

Part 4-10: Electromagnetic compatibility (EMC) – Transfer impedance and screening attenuation of feed-throughs and electromagnetic gaskets – Double coaxial test method

1 Scope

This part of IEC 62153 details a coaxial method suitable for determining the transfer impedance and/or screening attenuation of feed-throughs and electromagnetic gaskets.

The shielded screening attenuation test set-up according to IEC 62153-4-4 (triaxial method) has been modified to take into account the particularities of feed-throughs and gaskets.

A wide dynamic and frequency range can be applied to test even super screened feed-throughs and gaskets with normal instrumentation from low frequencies up to the limit of defined transversal waves in the coaxial circuits at approximately 4 GHz.

2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

Void.

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

3.1
operational (Betriebs) transfer function in the forward direction H_{B21}
operational (Betriebs) scattering parameter S_{21}
quotient of the reflected square root of power wave fed into the reference impedance of the output of the two-port and the unreflected square root of the power wave consumed at the input of the two-port

EXAMPLE (see Figure 1)